

400V N-ch Planar MOSFET

- **General Features RoHS Compliant**
- $R_{DS(ON),typ.}$ =0.78 Ω @ V_{GS} =10V
- Low Gate Charge Minimize Switching Loss
- Fast Recovery Body Diode

Applications

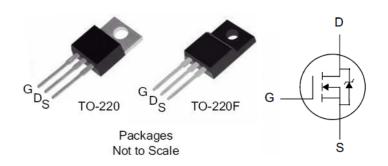
- Adaptor
- Charger
- SMPS Standby Power

Ordering Information

Part Number	Package	Brand
PSP06N40	TO-220	Z
PSA06N40	TO-220F	ĭ

(P6) Lead Free Package and Finish

BV _{DSS}	R _{DS(ON),Typ.}	I _D
400V	0.78Ω	6.0A



T_C=25 °C unless otherwise specified

Absolute Maximum Ratings

Symbol	Parameter	PSA06N40	PSP06N40	Unit	
V_{DSS}	Drain-to-Source Voltage	40	00	V	
V_{GSS}	Gate-to-Source Voltage	±	30	V	
I _D	Continuous Drain Current	6	.0	•	
I _{DM}	Pulsed Drain Current at V _{GS} =10V	24		Α	
E _{AS}	Single Pulse Avalanche Energy	200		mJ	
P _D	Power Dissipation	25	75	W	
r _D	Derating Factor above 25℃	0.2	0.60	W/°C	
T _L Leads at 0.063in (1.6mm) from Case for 10 seconds, Package Body for 10 seconds		300 260		°C	
T _J & T _{STG}	Operating and Storage Temperature Range	-55 to 150			

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

Thermal Characteristics

Symbol	Parameter	PSA06N40	PSP06N40	Unit
R _{eJC}	Thermal Resistance, Junction-to-Case	5.0	1.67	20.11
R _{θJA}	Thermal Resistance, Junction-to-Ambient	100	62	℃ /W



Electrical Characteristics

OFF Characteristics

T_J =25 ℃ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	400			٧	V _{GS} =0V, I _D =250uA
D : 1 0	Drain to Course Leglage Current			1	uA	V _{DS} =400V, V _{GS} =0V
I _{DSS}	Drain-to-Source Leakage Current			100		V_{DS} =320V, V_{GS} =0V, T_J =125 $^{\circ}$ C
	Gate-to-Source Leakage Current			+0.1		V _{GS} =+30V, V _{DS} =0V
I _{GSS}				-0.1	uA	V _{GS} =-30V, V _{DS} =0V

ON Characteristics

T_J =25 °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
R _{DS(ON)}	Static Drain-to-Source On-Resistance		0.78	1.0	Ω	V _{GS} =10V, I _D =3.0A
$V_{\text{GS(TH)}}$	Gate Threshold Voltage	2.0		4.0	V	V_{DS} = V_{GS} , I_D =250uA
gfs	Forward Transconductance		5.0		S	VDS=15V,ID=3.0A

Dynamic Characteristics

Essentially independent of operating temperature

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Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions	
C _{iss}	Input Capacitance		500			\/ -0\/	
C _{rss}	Reverse Transfer Capacitance		8.0		pF	V_{GS} =0V, V_{DS} =25V, f =1.0MH $_{Z}$	
C _{oss}	Output Capacitance		65				
Qg	Total Gate Charge		14.5				
Q_{gs}	Gate-to-Source Charge		3.0		nC	V_{DD} =200V, I_{D} =6A, V_{GS} =0 to 10V	
Q_{gd}	Gate-to-Drain (Miller) Charge		6.5				

Resistive Switching Characteristics Essentially

Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions
td(ON)	Turn-on Delay Time		8			
trise	Rise Time		10] 	V _{DD} =200V, I _D =6A,
td(OFF)	Turn-Off Delay Time		25		ns	V _{GS} =10V Rg=9.1 Ω
tfall	Fall Time		15			3



Source-Drain Body Diode Characteristics T_J=25 ℃ unless otherwise specified

Symbol	Parameter	Min	Тур.	Max.	Unit	Test Conditions
I _{SD}	Continuous Source Current ^[2]			6.0	۸	Integral pn-diode
I _{SM}	Pulsed Source Current ^[2]			24	Α	in MOSFET
V _{SD}	Diode Forward Voltage			1.5	V	I _S =6A, V _{GS} =0V
trr	Reverse Recovery Time		300		ns	V _G S=0V
Qrr	Reverse Recovery Charge		850		nC	I==6A, di/dt=100A/µs

Note:

^[1] T_J=+25 $^{\circ}$ C to +150 $^{\circ}$ C

^[2] Pulse width≤380µs; duty cycle≤2%.



Typical Characteristics

Figure 1. Maximun Forward Bias Safe Operating Area

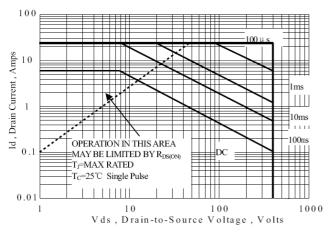


Figure 3. Maximum Continuous Drain Current vs Case Temperature

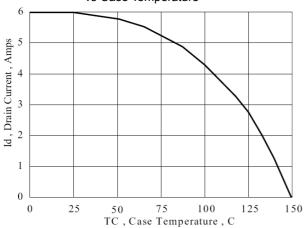


Figure 2. Maximun Power Dissipation vs Case Temperature

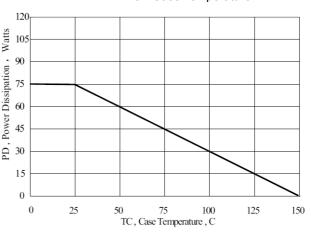


Figure 4. Typical Output Characteristics

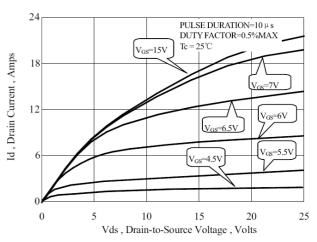
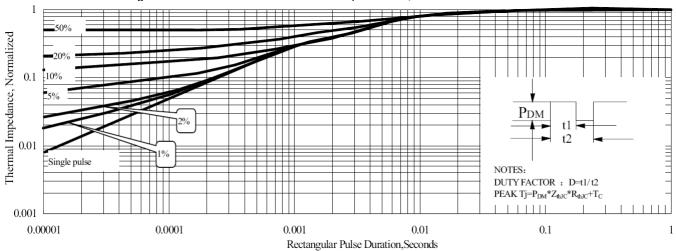


Figure 5. Maximum Effective Thermal Impendance, Junction to Case





Typical Characteristics(Cont.)

100 TEMPERATURES LIMIT TRANSCONDUCTANCE MAY ABOVE 25°C DERATE PEAK THIS REGION IN Idm, Peak Current, Amps CURRENT AS FOLLOWS: $150 - T_{c}$ 1.00E-05 1.00E-04 1.00E-03 1.00E-02 1.00E-01 1.00E+00 1.00E+01 t, Pulse Width, Seconds

Figure 6. MaximunPeak Current Capability

Figure 7. Typical Transfer Characteristics

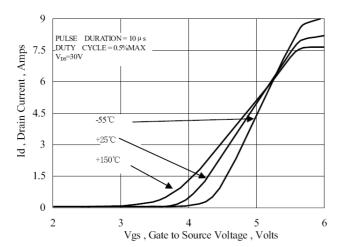


Figure 9. Typical Drain to Source ON Resistance vs Drain Current

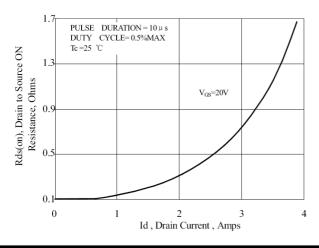


Figure .8 Typical Drain to Source ON Resistance vs Gate Voltage and Drain Current

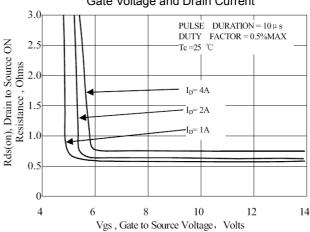
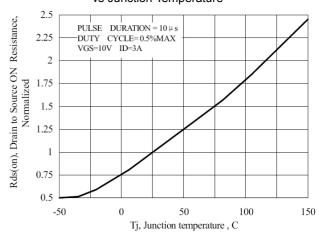


Figure 10. Typical Drian to Source on Resistance vs Junction Temperature





Typical Characteristics(Cont.)

Figure 11. Typical Theshold Voltage vs Junction Temperature

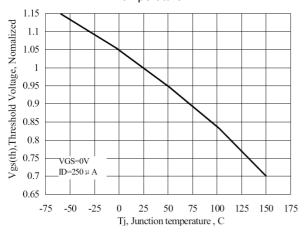


Figure 13. Typical Capacitance vs Drain to Source Voltage

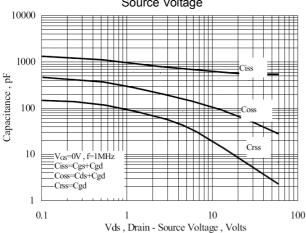


Figure 15. Typical Body Diode Transfer Characteristics

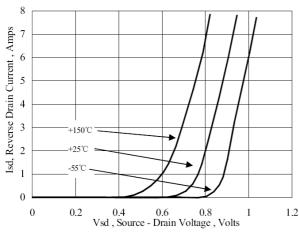


Figure 1.2 Typical Breakdown Voltage vs Junction Temperature

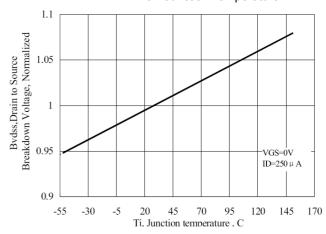


Figure 14. Typical Gate Charge vs Gate to Source Voltage

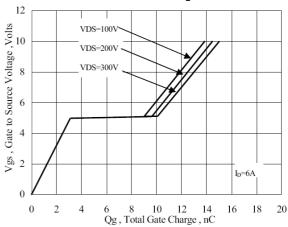
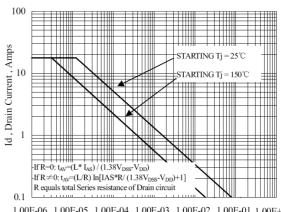


Figure 16. Unclamped Inductive Switching Capability



1.00E-06 1.00E-05 1.00E-04 1.00E-03 1.00E-02 1.00E-01 1.00E+00 tay,Time in Avalanche,Seconds



Test Circuits and Waveforms

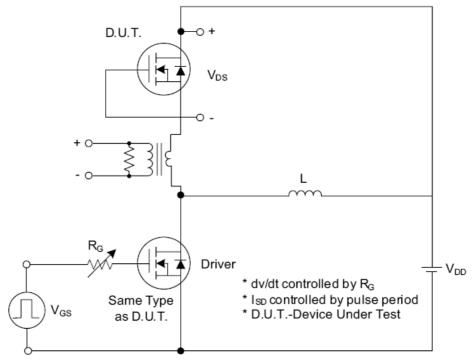


Fig. 1.1 Peak Diode Recovery dv/dt Test Circuit

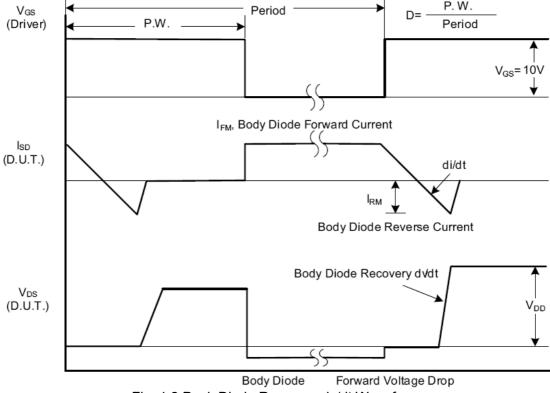


Fig. 1.2 Peak Diode Recovery dv/dt Waveforms



Test Circuits and Waveforms (Cont.)

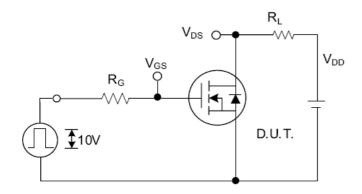


Fig. 2.1 Switching Test Circuit

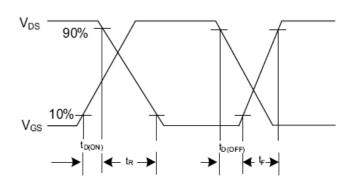


Fig. 2.2 Switching Waveforms

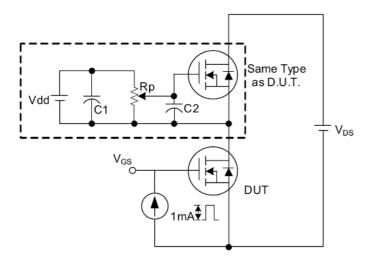


Fig. 3 . 1 Gate Charge Test Circuit

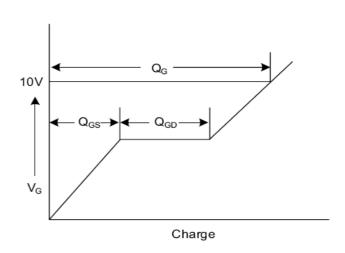


Fig. 3.2 Gate Charge Waveform

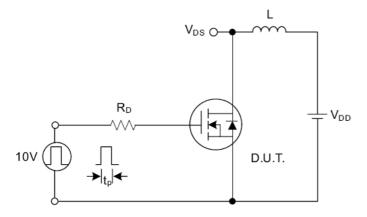


Fig. 4.1 Unclamped Inductive Switching Test Circuit

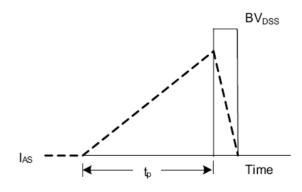


Fig. 4.2 Unclamped Inductive Switching Waveforms



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